## Notice of References Cited Application/Control No. 10/750,915 Examiner David A. Vanore Applicant(s)/Patent Under Reexamination OKUMURA ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,707,033	03-2004	Okumura et al.	250/281
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-		·	
	Н	US-			
	-	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name .	Classification
	N				,	
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	P					
	Q					
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## **NON-PATENT DOCUMENTS**

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